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FORM PTO-1449 (Modified) LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT	Docket: NH1.P01	Ser. No.: 09/632,383
	Applicant: John A. Ananian et al.	
	Filing Date: August 3, 2000	Group: 2771

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U.S. PATENT DOCUMENTS

Examiner Initial	*	Document No.	Date	Name	Class	Sub-Class
<i>h</i>	AA	6,037,945	03/14/00	Loveland	345	420
<i>h</i>	AB	6,014,503	01/11/00	Nagata et al.	395	500.01
<i>h</i>	AC	5,761,674	06/02/98	Ito	707	104
<i>h</i>	AD	5,557,537	09/17/96	Normann et al.	364	512
<i>h</i>	AE	5,555,406	09/10/96	Nozawa	395	500
<i>h</i>	AF	5,165,015	11/17/92	Coggins	395	155
<i>h</i>	AG	4,885,694	12/05/89	Pray et al.	364	464.01
<i>h</i>	AH	4,868,766	09/19/89	Oosterholt	364	522
<i>h</i>	AI	4,700,318	10/13/87	Ockman	364	518


FOREIGN PATENT DOCUMENTS

Examiner Initial	*	Document No.	Date	Name	Class	Sub-Class

OTHER ART (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

<i>h</i>	AJ	Archibus Inc., "Archibus/FM Web Central", "http://216.233.80.20/afm/doc/ Introduction.htm", July 17, 2000. <i>Chapter-1 pages 1-11</i>
<i>h</i>	AK	Booz Allen & Hamilton, "CAFM Selection and Implementation", "http://www.bah.com/fso/cafm.html", last modified August 20, 2000. <i>1999 pages 1-4 only</i>
<i>h</i>	AM	XML, "Integration of Parts: XSLT, Xlink, and SVG", "http://www.xml.com/pub/2000/03/22/style/index.html", July 13, 2000. <i>pages 1-13 only</i>
<i>h</i>	AN	FotoG, "Close Range Photogrammetry", "http://www.vexcel.com/fotog", July 11, 2000. <i>one page only</i>
<i>h</i>	AO	Comfortlife, "Measuring Devices", "http://www.sgfa.com/comfortlife/eletronic tapes.html", July 11, 2000. <i>5 pages only</i>
<i>h</i>	AP	MicroStation, "Plant Engineering", "http://www.msmonline.com/extra/jan00/plant1.htm", July 11, 2000. <i>1-5 pages</i>
<i>h</i>	AQ	Service Magic, "Start A New Home Project", "http://www.servicemagic.com/cgi-bin/servicemagic/scripts/Index.jsp", May 8, 2000. <i>6 pages only</i>

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	AR	MIT Media Laboratory, "HandSCAPE: A Vectorizing Tape Measure for On-Site Measuring Applications", April 1-6 2000, ACM Press. <i>Pages 1-8</i>
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Examiner: <i>SRIRAMA CHANNAVAJALA</i>	Date Considered <i>4/28/2003</i>
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